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TEST REPORT ON HAC

Model Tested:	SCH-R220
FCC ID (Requested):	A3LSCHR220
Job No:	AI-076
Report No:	AI-076-T1
Date issued:	Jan 19, 2012
Result Summary:	T4 – 2007 (Signal To Noise Category)

- Abstract -

This document reports on HAC Tests carried out in accordance with ANSI C63.19(2007) §6.3, §7.3, FCC Rule Part(s) FCC 47 CFR §20.19

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Report Number : AI-076-T1

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1. GENERAL INFORMATION

Test Sample : Cellular/PCS CDMA Phone with Bluetooth
Model Number : SCH-R220
Additional Model: None
Serial Number : Identical prototype (S/N : AI-076-B)
Manufacturer : SAMSUNG ELECTRONICS Co., Ltd.
Address : 416 Maetan3-Dong, Yeongtong-gu, Suwon City
Gyeonggi-Do, Korea 443-742
Test Standard : ANSI C63.19 (2007) §6.3, §7.3, FCC 47 CFR § 20.19
FCC Classification : Licensed Portable Transmitter Held to Ear (PCE)
Test Dates : Jan 09, 2012
Tested for : FCC/TCB Certification

2. DESCRIPTION OF DEVICE

Tx Freq. Range : 824.7 ~ 848.31 MHz(CDMA)
1851.25 ~ 1908.75 MHz(PCS)

Rx Freq. Range : 869.7 ~ 893.31 MHz(CDMA)
1931.25 ~ 1988.75 MHz(PCS)

Antenna Configuration : Gen4-0526
Antenna Manufacturer : Max Skylink
Antenna Dimensions : 38 * 15 * 6.7 (mm)

Indicating Operating modes for Air Interfaces/Bands

Air-Interface	Band(MHz)	Type	C63.19 - 2007 Tested	Simultaneous Transmissions Note: Not to be tested	Reduced Power 20.19 (c)(1)	Voice Over Digital Transport (Data)
CDMA	835	Voice	Yes	Yes: BT	N/A	N/A
CDMA	1900	Voice	Yes	Yes: BT	N/A	N/A
CDMA	All Band (835,1900)	Data	N/A	N/A	N/A	N/A
BT	2450	Data	N/A	N/A	N/A	N/A

* HAC Rating was not based on concurrent voice and data mode.

Standalone mode was found to represent worst case rating for both M and T rating

3. Performance

3.1 RF EMISSIONS

The ANSI Standard presents performance requirements for acceptable interoperability of hearing aids with wireless communications devices. When these parameters are met, a hearing aid operates acceptably in close proximity to a wireless communications device.

Category	Telephone RF Parameters	
Near field Category	E-field emissions CW dB(V/m)	H-field emissions CW dB(A/m)
f < 960 MHz		
M1	56 to 61 + 0.5 x AWF	5.6 to 10.6 +0.5 x AWF
M2	51 to 56 + 0.5 x AWF	0.6 to 5.6 +0.5 x AWF
M3	46 to 51 + 0.5 x AWF	-4.4 to 0.6 +0.5 x AWF
M4	< 46 + 0.5 x AWF	< -4.4 + 0.5 x AWF
f > 960 MHz		
M1	46 to 51 + 0.5 x AWF	-4.4 to 0.6 +0.5 x AWF
M2	41 to 46 + 0.5 x AWF	-9.4 to -4.4 +0.5 x AWF
M3	36 to 41 + 0.5 x AWF	-14.4 to -9.4 +0.5 x AWF
M4	< 36 + 0.5 x AWF	< -14.4 + 0.5 x AWF
Table 4-1 Hearing aid and WD near-field categories as defined in ANSI C63.19-2007 [2]		

3.2 ARTICULATION WEIGHTING FACTOR (AWF)

Standard	Technology	Articulation Weighing Factor (AWF)
T1/T1P1/3GPP	UMTS (WCDMA)	0
TIA/EIA/IS-2000	CDMA	0
iDEN™	TDMA (22 and 11 Hz)	0
J-STD-007	GSM (217 Hz)	-5
Table 4-2 Articulation Weighting Factors		

3.3 MAGNETIC COUPLING

Axial and Radial Field Intensity

All orientations of the magnetic field, in the axial, horizontal and vertical position along the measurement plane shall be ≥ -18 dB(A/m) at 1 kHz in a 1/3 octave band filter per 7.3.1.

Frequency Response

The frequency response of the axial component of the magnetic field shall follow the response curve specified in EIA RS-504-1983, over the frequency range 300 Hz – 3000 Hz per 7.3.2.

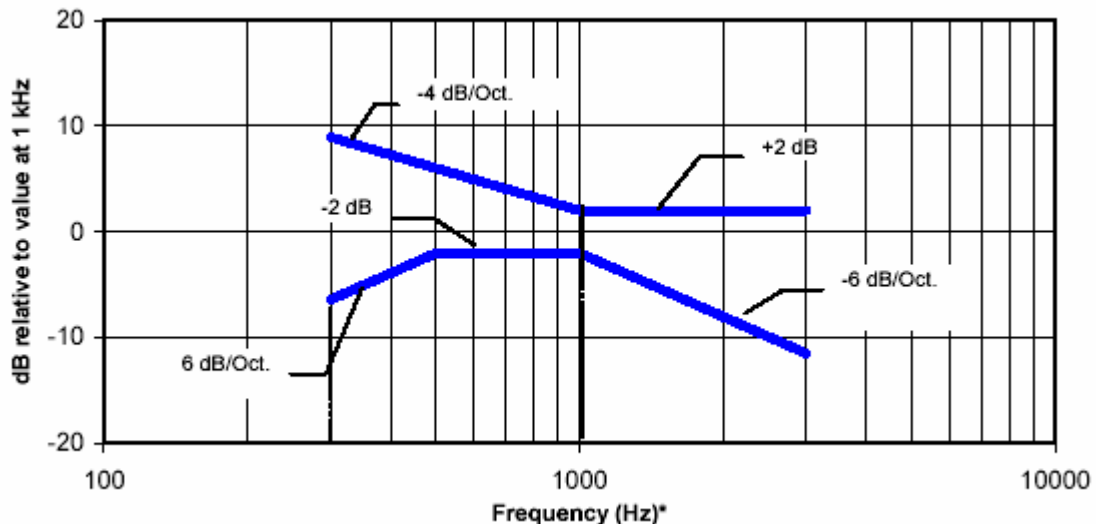


Figure 4-1

Magnetic field frequency response for Wireless Devices with an axial field below ≤ -15 dB (A/m) at 1 kHz

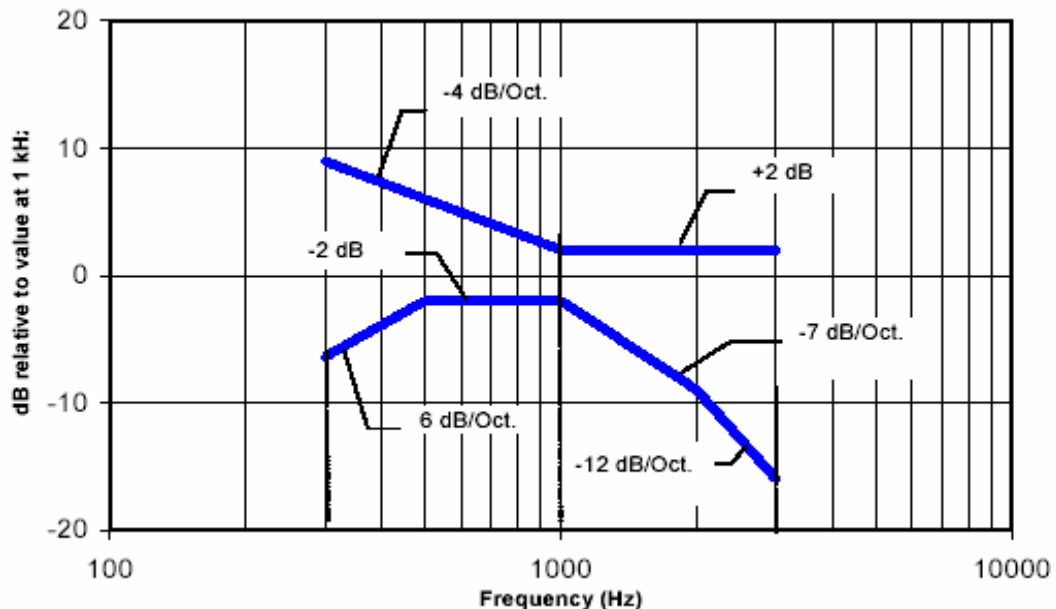


Figure 4-2

Magnetic Field frequency response for wireless devices with an axial field that exceeds -15 dB(A/m) at 1 kHz

Signal Quality

The table below provides the signal quality requirement for the intended audio magnetic signal from a wireless device. Only the RF immunity of the hearing aid is measured in T-coil mode. It is assumed that a hearing aid can have no immunity to an interference signal in the audio band, which is the intended reception band for this mode. The only criterion that can be measured is the RF immunity in T-coil mode. This is measured using the same procedure as the audio coupling mode at the same levels.

The signal quality of the axial and radial components of the magnetic field was used to determine the T-coil mode category.

Category	Telephone RF Parameters
	Wireless Device Signal Quality (Signal + Noise-to-noise ratio in dB)
T1	0 to 10 dB
T2	10 to 20 dB
T3	20 to 30 dB
T4	> 30 dB

Table 4-3
Magnetic Coupling Parameters

4. DESCRIPTION OF TEST EQUIPMENT

4.1 HAC Measurement Setup

The equipment was connected as shown in an acoustic/RF hemi-anechoic chamber:

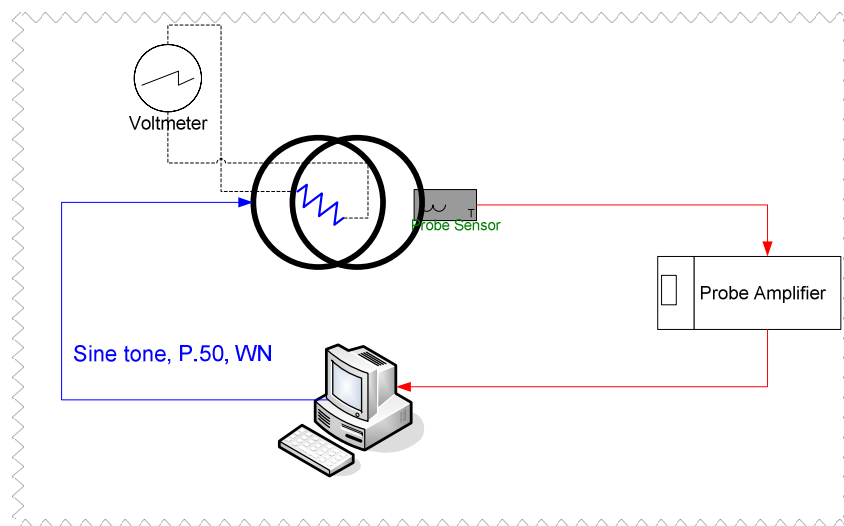


Figure 4-1 Validation Setup with Helmholtz Coil

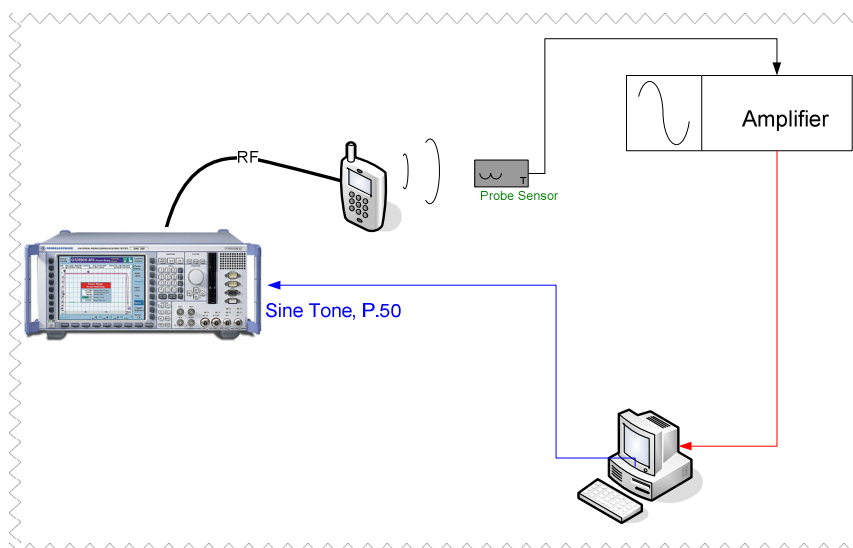


Figure 4-2 T-Coil Test Setup

4.2 Scanning Mechanism

Manufacturer:	TEM
Accuracy:	± 0.83 cm/meter
Minimum Step Size:	0.1 mm
Maximum speed	6.1 cm/sec
Line Voltage:	115 VAC
Line Frequency:	60 Hz
Material Composite:	Delrin (Acetal)
Data Control:	Parallel Port
Dynamic Range (X-Y-Z):	45 x 31.75 x 47 cm
Dimensions:	36" x 25" x 38"
Operating Area:	36" x 49" x 55"
Reflections:	< -20 dB (in anechoic chamber)

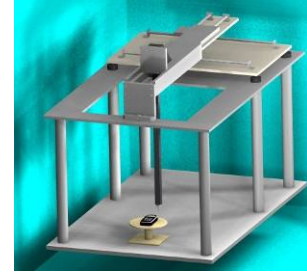


Figure 4-3
RF Near-Field Scanner

4.3 ITU-T P.50 Artificial Voice

Manufacturer:	ITU-T
Active Frequency Range:	100 Hz – 8 kHz
Stimulus Type:	Male and Female, no spaces
Single Sample Duration:	20.96 seconds
Activity Level:	100%

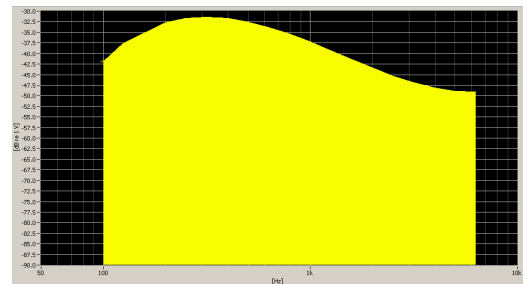


Figure 4-4
Spectral Characteristic of full P.50

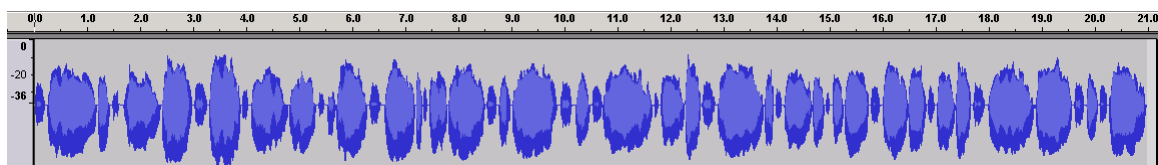
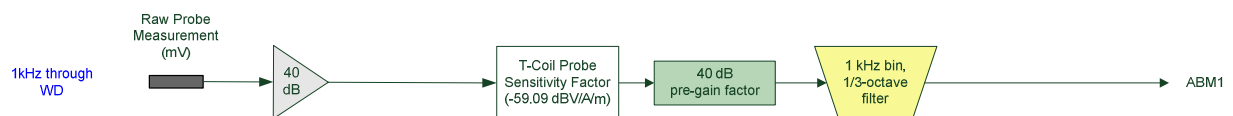


Figure 4-5
Temporal Characteristic of full P.50

ABM1 Measurement Block Diagram:



ABM2 Measurement Block Diagram:

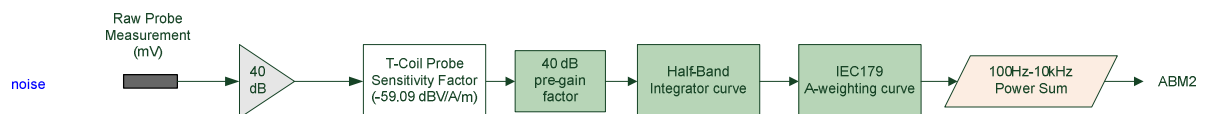


Figure 4-6 Magnetic Measurement Processing Steps

4.4 Equipment Calibration
Table 3.2 Test Equipment Calibration

Model	Description	Cal. Due Date	Serial No.
CMU200	Base Station Simulator	Oct/12/2012	109162
4474	Data Acquisition Card	N/A	N/A
Positioner	HAC Positioner	N/A	N/A
HAC System	HAC System controller with S/W	N/A	N/A
Axial T-coil Probe	Axial T-coil Probe	Jan/14/2012	TEM-1115
Radial T-coil Probe	Radial T-coil Probe	Jan/14/2012	TEM-1119
E4440A	PSA Spectrum analyzer	Feb/24/2012	MY45304704
E4419B	EPM Power Meter	Feb /25/2012	MY45103291
E9300B	Power Sensor	Mar/4/2012	MY41496209
Fluke87	RMS Multimeter	Dec/20/2012	65030199
E3640A	Power supply	Dec/19/2012	MY40009112
AMCC	H/H coil(Speag)	N/A	N/A

5. HAC MEASUREMENT PROCEDURE

The flow diagram below was followed (From C.63.19):

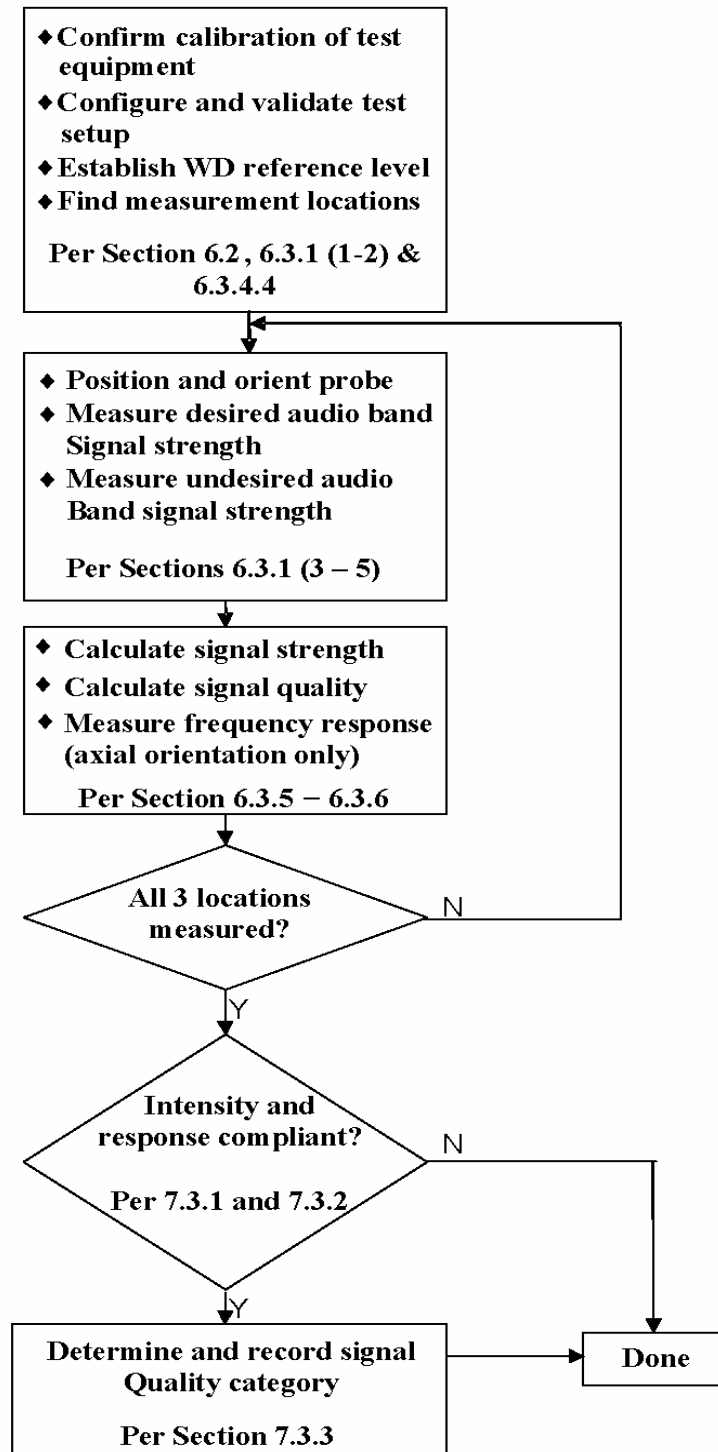


Figure 5-1 Test Procedure for T-coil Measurement

5.1 Ambient Noise Check per C63.19 §6.2.1

- Ambient interference was monitored using a Real-Time Analyzer between 100-10,000 Hz with 1/3 octave filtering.
- “A-weighting” and Half-Band Integration was applied to the measurements.
- Since this measurement was measured in the same method as ABM2 measurements, this level was verified to be less than 10 dB below the lowest measurement signal (which is the highest ABM2 measurement for a T4 WD). Therefore the maximum noise level for a T4 WD with an ABM1 = -18 dBA/m is:

$$-18 - 30 - 10 = -58 \text{ dBA/m}$$

5.2 Measurement System Validation (See Figure 4-1)

- The measurement system including the probe, pre-amplifier and acquisition system were validated as an entire system to ensure the reliability of test measurements.
- ABM1 Validation
 The magnetic field at the center of the Helmholtz coil is given by the equation (per C63.19 Annex D.9.1):

$$H_c = \frac{NI}{r\sqrt{1.25^3}} = \frac{N(\frac{V}{R})}{r\sqrt{1.25^3}}$$

Where H_c = magnetic field strength in amperes per meter
 N = number of turns per coil

For a Helmholtz Coil, N=20; r=0.143m; R=10.2Ω and using V=102mV:

$$H_c = \frac{20 \cdot (\frac{0.102}{10.2})}{0.143 \cdot \sqrt{1.25^3}} = 1.0007 \text{ A/m}$$

Therefore a pure tone of 1kHz was applied into the coils such that 102 mV was observed across the 10.2 Ω resistor. The voltmeter used for measurement was verified to be capable of measurements in the audio band range. This theoretically generates an expected field of 1 A/m in the center of the Helmholtz coil which was used to validate the probe measurement at 1 A/m. This was verified to be within ± 0.5 dB of the 1 A/m value.

- Frequency Response Validation

The frequency response through the Helmholtz Coil was verified to be within 0.5 dB relative to 1 kHz, between 300 – 3000 Hz using the ITU-P.50 artificial speech signal as shown below:

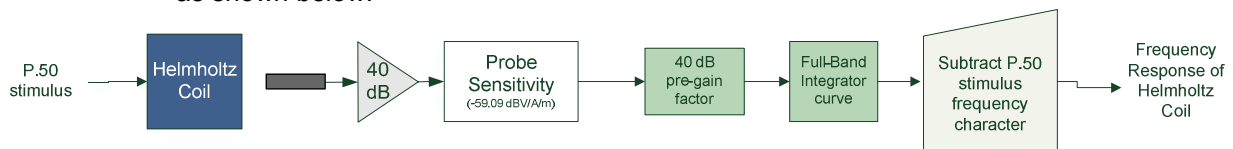


Figure 5-2 Frequency Response Validation

- ABM2 Measurement Validation

WD noise measurements are filtered with A-weighting and Half-Band Integration over a frequency range of 100Hz – 10kHz to process ABM2 measurements. Below is the verification of the system processing A-weighting and Half-Band integration between system input to output within 0.5 dB of the theoretical result:

Table 5-1
ABM2 Frequency Response Validation

f (Hz)	HBI, A - Measured (dB re 1kHz)	HBI, A - Theoretical (dB re 1kHz)	dB Var.
100	-16.180	-16.170	-0.010
125	-13.257	-13.250	-0.007
160	-10.347	-10.340	-0.007
200	-8.017	-8.010	-0.007
250	-5.925	-5.920	-0.005
315	-4.045	-4.040	-0.005
400	-2.405	-2.400	-0.005
500	-1.212	-1.210	-0.002
630	-0.349	-0.350	0.001
800	0.071	0.070	0.001
1000	0.000	0.000	0.000
1250	-0.503	-0.500	-0.003
1600	-1.513	-1.510	-0.003
2000	-2.778	-2.780	0.002
2500	-4.316	-4.320	0.004
3150	-6.166	-6.170	0.004
4000	-8.322	-8.330	0.008
5000	-10.573	-10.590	0.017
6300	-13.178	-13.200	0.022
8000	-16.241	-16.270	0.029
10000	-19.495	-19.520	0.025

ABM2 Frequency Response Validation (LISTEN)

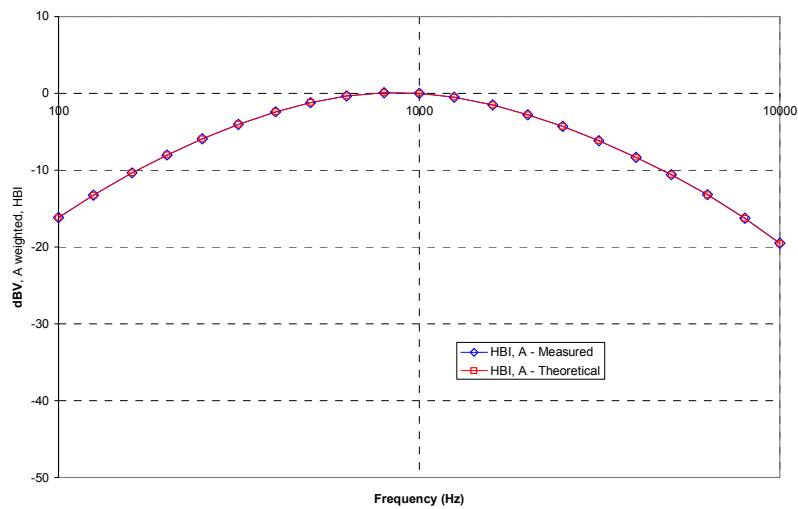


Figure 5-3
ABM2 Frequency Response Validation

The ABM2 result is a power sum from 100 Hz to 10 kHz with half-band integration and A-weighting. To verify the power sum measurement, a power sum over the full band was measured and verified to track with the source level (See Figure 5-9). Therefore the setup in this step was used to verify the power sum post-processing for ABM2 measurements. See below block diagram:

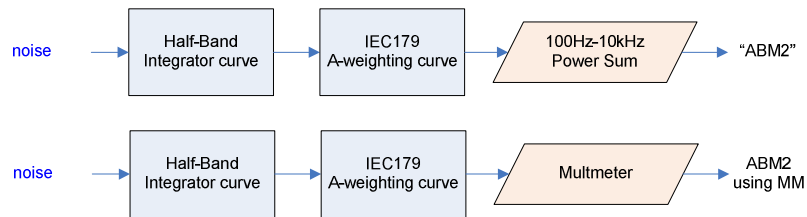


Figure 5-4 ABM2 Validation Block Diagram

The power summed output results for a known input were compared to the multi-meter results to verify any deviation in the post-processing implemented with the power-sum.

Table 5-2 ABM2 Power Sum Validation

WN Input (dBV)	Power Sum (dBV)	Multimeter-Full (dBV)	Dev (dB)
-60	-60.36	-60.2	0.16
-50	-50.19	-50.13	0.06
-40	-40.14	-40.03	0.11
-30	-30.13	-30.01	0.12
-20	-20.12	-20	0.12
-10	-10.14	-10	0.14

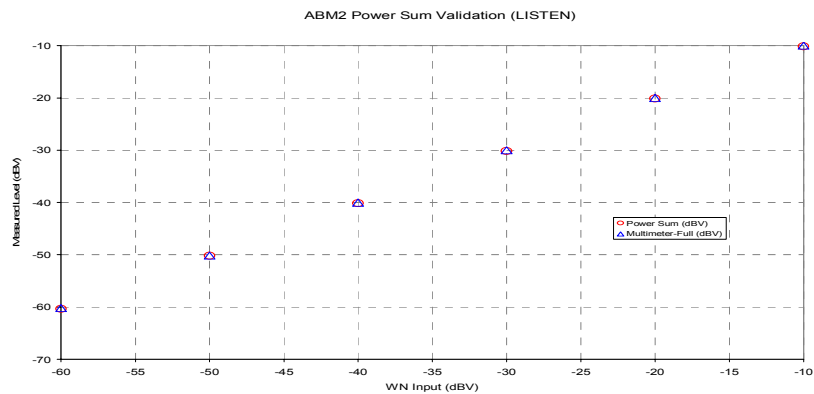


Figure 5-5 ABM2 Power Sum Validation

5.3 Measurement Test Setup

5.3.1 Fine scan above the WD (TEM)

- a. A multi-tone signal was applied to the handset such that the phone acoustic output was stable within 1dB over the probe settling time and with the acoustic output level at the C63.19 specified levels (below). The measurement step size was in 2 mm increments at a distance of 10 mm between the surface of the wireless device as shown below:

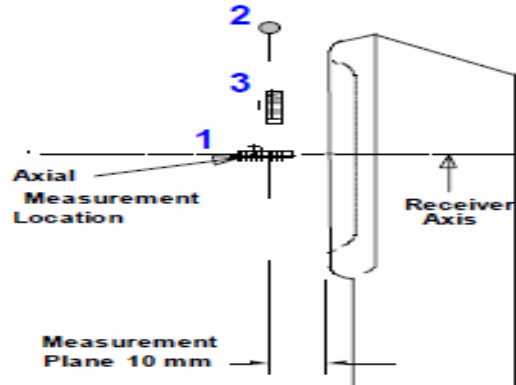


Figure 5-6
Measurement Distance

- b. After scanning, the planar field maximum point was determined. The position of the probe was moved to this location to setup the test using the sound check system.
- c. These steps were repeated for the other T-coil orientations (of axial, radial transverse, or radial longitudinal) per Figure 5-16 after a T-coil orientation was fully measured with the sound check system.

5.3.2 Speech Signal Setup to Base Station Simulator

- a. C63.19 Table 6-1 states audio reference input levels for various technologies:

Standard	Technology	Input Level (dBm0)
TIA/EIA/IS-2000	CDMA	-18
J-STD-007	GSM (217)	-16
T1/T1P1/3GPP	UMTS (WCDMA)	-16
iDEN™	TDMA (22 and 11 Hz)	-18

The CMU200 audio levels were determined using base station simulator manufacturer calibration procedures resulting in the below corresponding voltages relative to handset test point level (in dBm0):

Table 5-3
CMU200 Voltage Input Levels for Audio

	CDMA				
	Decoder Cal.		Encoder Cal.		Sensitivity (DUT R)
	Peak 1(mV)	Peak 1(dBV)	Peak 1(mV)	Peak 1(dBV)	
3.16dBm0	1039.11	0.33	1039.22	0.33	1.077
-18dBm0			91.11	-20.81	

* Encoder cal. value adjusts to Decoder cal. value.

- b. Real-Time Analyzer (RTA)
 - i. The Real-Time Analyzer was configured to analyze measurements using 1/3 Octave band weighted filtering.
- c. WD Radio Configuration Selection
 - i. The device was chosen to be tested in the worst-case ABM2 condition under Radio Configurations and Service Options for CDMA(see below):

XY Graph 1

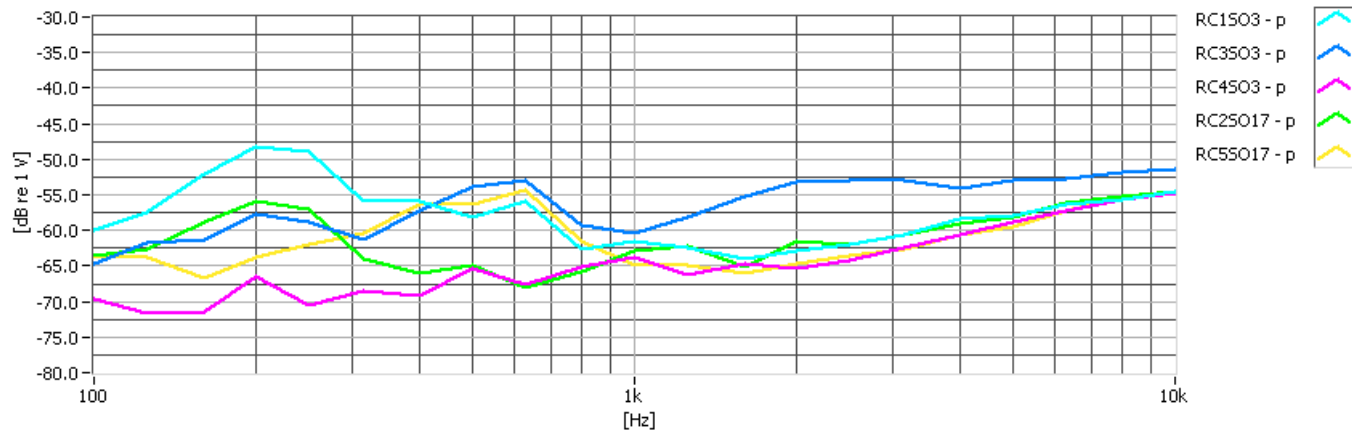


Figure 5-7 Vocoder Analysis for ABM Noise (CDMA)

Table 5-4
The ABM2 levels among various RC/SO

ABM2 Pre-Test (dBA/m)						
RC1/SO3	RC3/SO3	RC2/SO17	RC5/SO17	RC4/SO3	Orientation	Channel
-40.44	-44.17	-47.54	-46.76	-53.78	Axial	600

5.3.3 Signal Quality Data Analysis

- a. Narrow-band Magnetic Intensity
 - i. The standard specifies a 1 kHz 1/3 octave band minimum field intensity for a sine tone. The ABM1 measurements were evaluated at 1kHz with 1/3 octave band filtering over an averaged period of 10 seconds.
- b. Frequency Response
 - i. The appropriate frequency response curve was measured to curves in Figure 4-1 or Figure 4-2 between 300 – 3000 Hz using digital linear averaging (limit lines chosen according to measurement found in step 4a.) A linear average over 3x the length of the artificial voice signal (3x sampling) was performed. A 10 second delay was configured in the measurement process of the stimulus to ensure handset vocoder latency effects and echo cancellation devices (if any) were appropriately stabilized during measurements.
 - ii. The appropriate post-processing was applied according to the system processing chain illustrated in Figure 5-13. All R10 frequencies were plotted with respect to 0dB at 1 kHz value and aligned with respect to the EIA-504 mask.

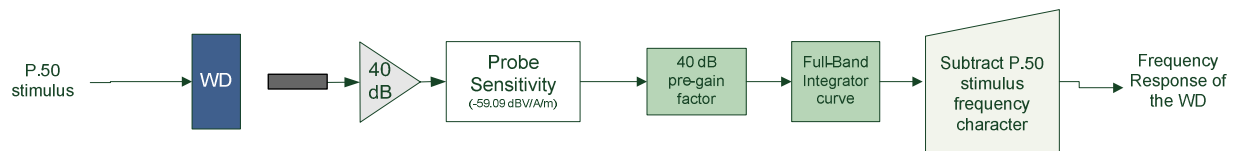


Figure 5-8 Frequency Response Block Diagram

- iii. The margin is represented by the closest measured data point on the curve to the EIA-504 limit lines, in dB.
- c. Signal Quality Index
 - i. Ensuring the WD was at maximum RF power, maximum volume, backlight on, display on, maximum contrast setting, keypad lights on (when possible) with no audio signal through the vocoder, the WD was measured over at least 100 Hz – 10,000 Hz, maximized over 5 seconds with a 50ms sample time for the ABM2 measurement (5 second time period is used in noise measurements under standards such as IEEE 269, etc.)
 - ii. After applying half-band integration and A-weighting to the result, a power sum was applied over each 1/3 octave bandwidth frequency for an ABM2 value
 - iii. This result was subtracted from the ABM1 result in step a, to obtain the Signal Quality.

5.3.4 Wireless Device Channels and Frequencies

The frequencies listed in the table below are those that lie in the center of the bands used for cellular telephony. Low, middle and high channels were tested in each band for FCC compliance evaluation to ensure the maximum emission is captured across the entire band.

To facilitate setting of a base station simulator for ABM measurements, specific band plan channel numbers are listed that may be used in lieu of the band center frequencies.

**Table 5-5
Center Channels and Frequencies**

Test frequencies & associated channels	
Channel	Frequency (MHz)
Cellular 850	
384 (CDMA)	836.52
UARFCN 4183(UMTS)	836.60
190 (GSM)	836.60
AWS 1730	
450 (CDMA)	1732.5
UARFCN 1412 (UMTS)	1732.4
PCS 1900	
661 (GSM)	1880
600 (CDMA)	1880
UARFCN 9400 (UMTS)	1880

5.3.5 RF Emission Effect on T-coil Measurements

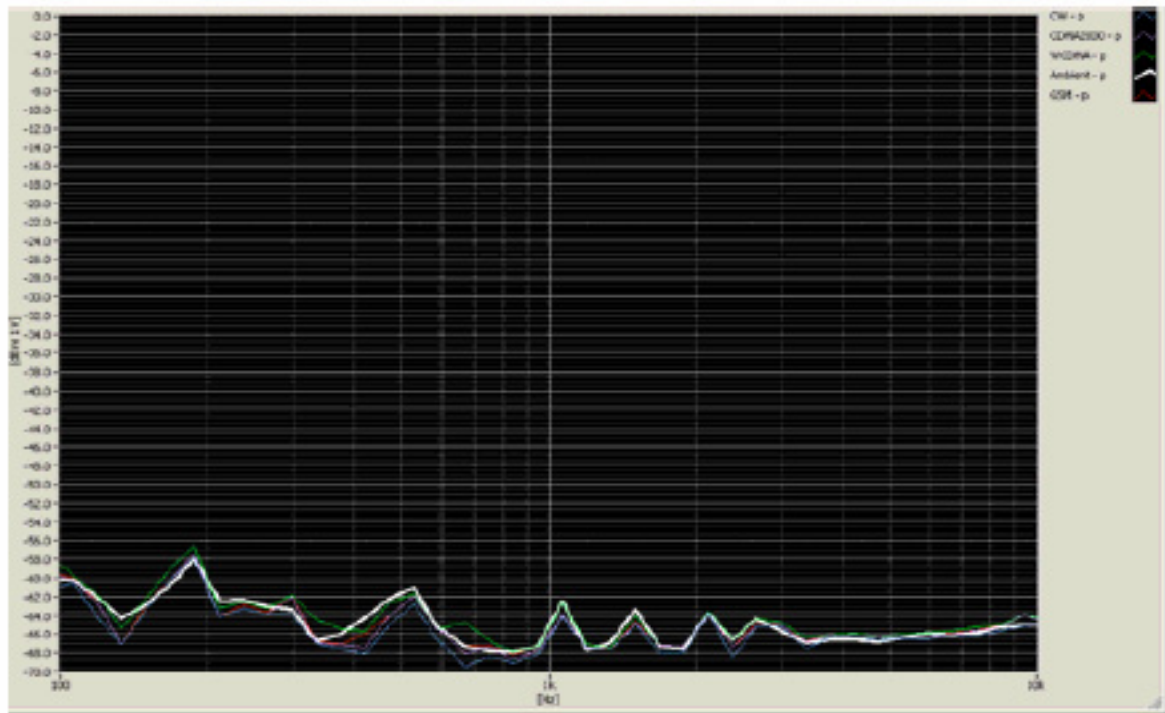


Figure 5-9

High Power RF Emissions Effect with HAC Dipole on the T-coil Probe System 10mm between dipole maximum and magnetic probe

6. MEASUREMENT UNCERTAINTY

Source of Uncertainty	Value %	Probability distribution	Divisor	c_i	$u_i(y)$	$(u_i(y))^2$	v_i OR v_{eff}	$u_i(y)^4/v_{eff}$
Measurement system								
ABM Noise	0.16	normal	1.000	1	0.16	0.024	4	0.0001469
RF Reflection	4.70	rectangular	1.732	1	2.71	7.363	∞	0
Reference Signal Level	12.20	rectangular	1.732	1	7.04	49.613	∞	0
Probe Coil Sensitivity	12.20	rectangular	1.732	1	7.04	49.613	∞	0
Probe Linearity	2.40	rectangular	1.732	1	1.39	1.920	∞	0
Cable Loss	2.80	rectangular	1.732	1	1.62	2.613	∞	0
Frequency Analyzer	5.00	rectangular	1.732	1	2.89	8.333	∞	0
System Repeatability	2.04	normal	1.000	1	2.04	4.176	4	4.360
Positioner Accuracy	1.00	rectangular	1.732	1	0.58	0.333	∞	0
Test sample related								
WD Repeatability	10.40	normal	1.000	1	10.40	108.137	4	2923.396
Phantom and set-up								
Positioning Accuracy	9.75	normal	1.000	1	9.75	95.045	4	2258.375
Combined Standard Uncertainty		normal			18.09	327.172	21	5186.131
Expanded Uncertainty		normal k=	2		35.45		21	

Notes:

1. Test equipments are calibrated according to techniques outlined in NIS81, NIS3003 and NIST Tech Note 1297.
2. All equipments have traceability according to NIST. Measurement Uncertainties are defined in further detail in NIS 81 and NIST Tech Note 1297 and UKAS M3003.

Measurement uncertainty reflects the quality and accuracy of a measured result as compared to the true value. Such statements are generally required when stating results of measurements so that it is clear to the intended audience that the results may differ when reproduced by different facilities. Measurement results vary due to the measurement uncertainty of the instrumentation, measurement technique, and test engineer. Most uncertainties are calculated using the tolerances of the instrumentation used in the measurement, the measurement setup variability, and the technique used in performing the test. While not generally included, the variability of the equipment under test also figures into the overall measurement uncertainty. Another component of the overall uncertainty is based on the variability of repeated measurements (so-called Type A uncertainty). This may mean that the Hearing Aid compatibility tests may have to be repeated by taking down the test setup and resetting it up so that there are a statistically significant number of repeat measurements to identify the measurement uncertainty. By combining the repeat measurement results with that of the instrumentation chain using the technique contained in NIS 81 and NIS 3003, the overall measurement uncertainty was estimated.

7. Test Results

7.1 Test Summary

Table 7-1
Table of Results for CDMA

Mode	Band	Orientation	Measurement Item	Limit	Measured	Verdict	Result
CDMA	Cellular	Axial	Intensity	-18	16.83	PASS	T4
			Frequency Response	0	2	PASS	
			SNNR	20	57.58	PASS	
		Radial Transverse	Intensity	-18	7.92	PASS	
			Frequency Response	0	2	PASS	
			SNNR	20	58.91	PASS	
		Radial Longitudinal	Intensity	-18	7.4	PASS	
			Frequency Response	0	2	PASS	
			SNNR	20	55.31	PASS	
	PCS	Axial	Intensity	-18	16.76	PASS	T4
			Frequency Response	0	2	PASS	
			SNNR	20	64.02	PASS	
		Radial Transverse	Intensity	-18	7.87	PASS	
			Frequency Response	0	2	PASS	
			SNNR	20	59.93	PASS	
		Radial Longitudinal	Intensity	-18	7.29	PASS	
			Frequency Response	0	2	PASS	
			SNNR	20	54.59	PASS	

*Note : The above results are tested in the worst case of ABM2 configuration.
(According to table 5-4, the worst case is CDMA RC3SO3 configuration)

The measured T-coil category is T4 for CDMA mode and all raw data is in Section 7.2.

7.2 Raw Data for T-coil Measurement

Table 7-2
Raw Data for CDMA

	CDMA								
	Axial			Radial Transverse			Radial Longitudinal		
	Ch.1013	Ch.384	Ch.777	Ch.1013	Ch.384	Ch.777	Ch.1013	Ch.384	Ch.777
ABM1 (dBA/m)	16.83	16.87	17.1	7.92	8.02	7.95	7.42	7.4	7.68
ABM2(dBA/m)	-40.75	-46.15	-48.05	-54.97	-51.23	-50.96	-47.88	-49.08	-48.05
Frequency Response(dB)	2	2	2	2	2	2	2	2	2
SNNR(dB)	57.58	63.01	65.15	62.89	59.25	58.91	55.31	56.48	55.73
Ambient Noise(dBA/m)	-60.29			-59.06			-58.66		
Minimum of SNNR	57.58			58.91			55.31		
T-coil Coordinates (cm)	2.6,2.6			3.4,2.6			2.6,3.4		

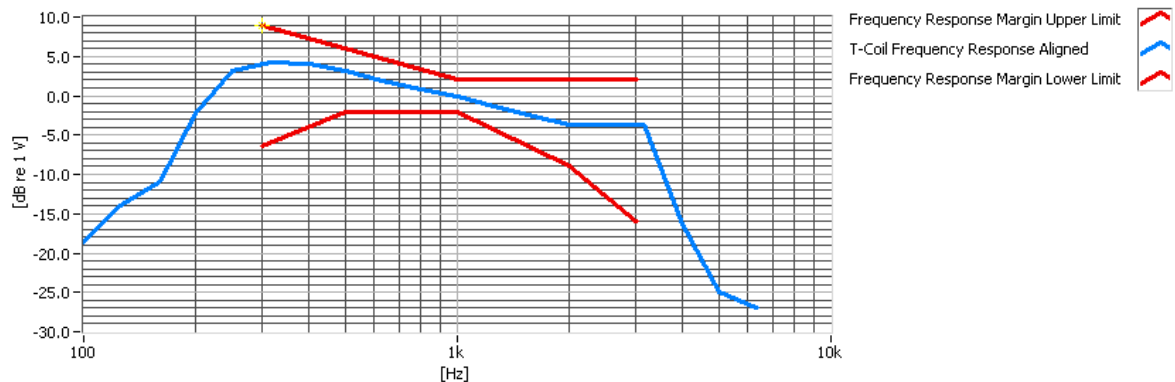
	PCS								
	Axial			Radial Transverse			Radial Longitudinal		
	Ch.25	Ch.600	Ch.1175	Ch.25	Ch.600	Ch.1175	Ch.25	Ch.600	Ch.1175
ABM1 (dBA/m)	16.84	16.76	16.83	7.98	8.18	7.87	7.33	7.29	7.29
ABM2(dBA/m)	-48.38	-51.65	-47.19	54.21	-51.75	-54.61	-47.26	-48.05	-48.39
Frequency Response(dB)	2	2	2	2	2	2	2	2	2
SNNR(dB)	65.22	68.4	64.02	62.19	59.93	62.49	54.59	55.34	55.68
Ambient Noise(dBA/m)	-60.29			-59.06			-58.66		
Minimum of SNNR	64.02			59.93			54.59		
T-coil Coordinates (cm)	2.6,2.6			3.4,2.6			2.6,3.4		

WD Configuration :

1. Power configuration : Power Control Bits = "All Up"
2. Phone condition : Mute On, Backlight On, Max Volume, Max Contrast
3. Radio Configuration : RC3/SO3 (8K EVRC(Low))

7.3 Frequency Response Graph

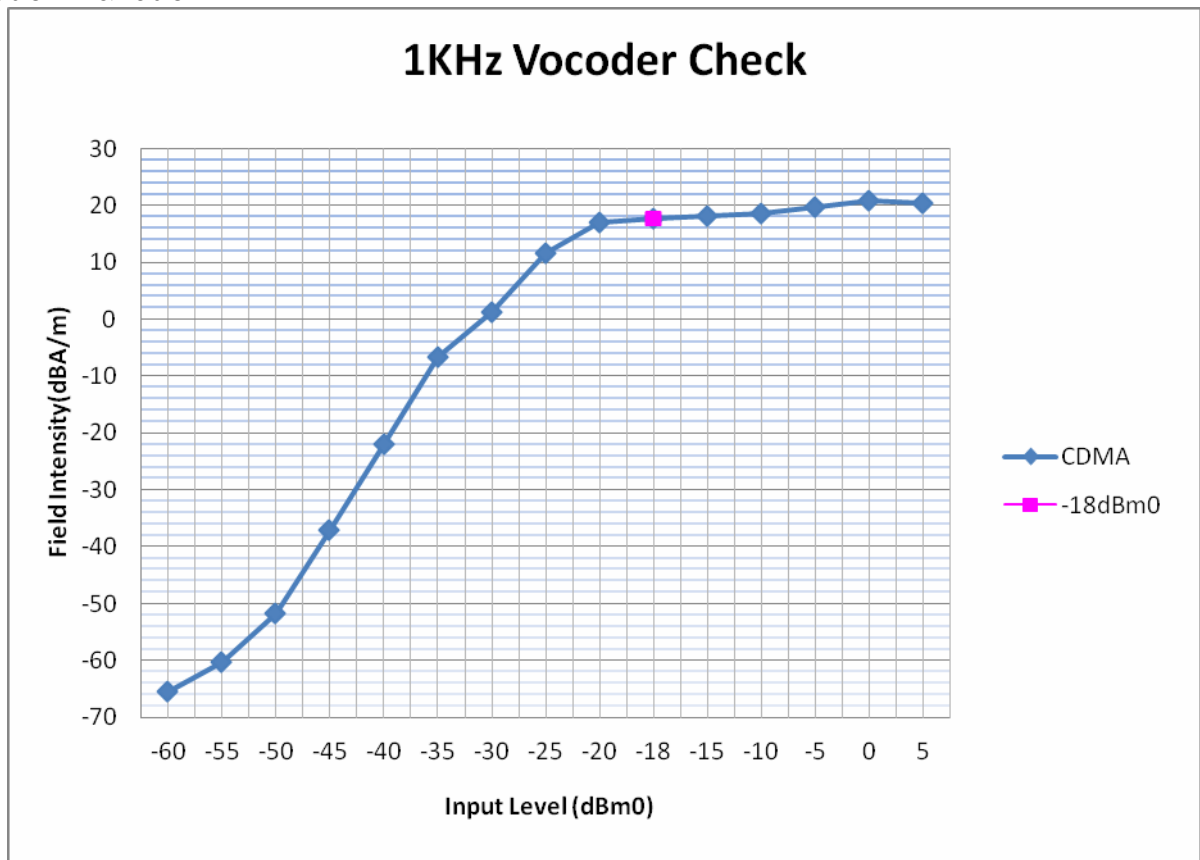
XY Graph 1



Note : This frequency response represents the worst-case ABM2 test configuration according to Table 7-2 for CDMA

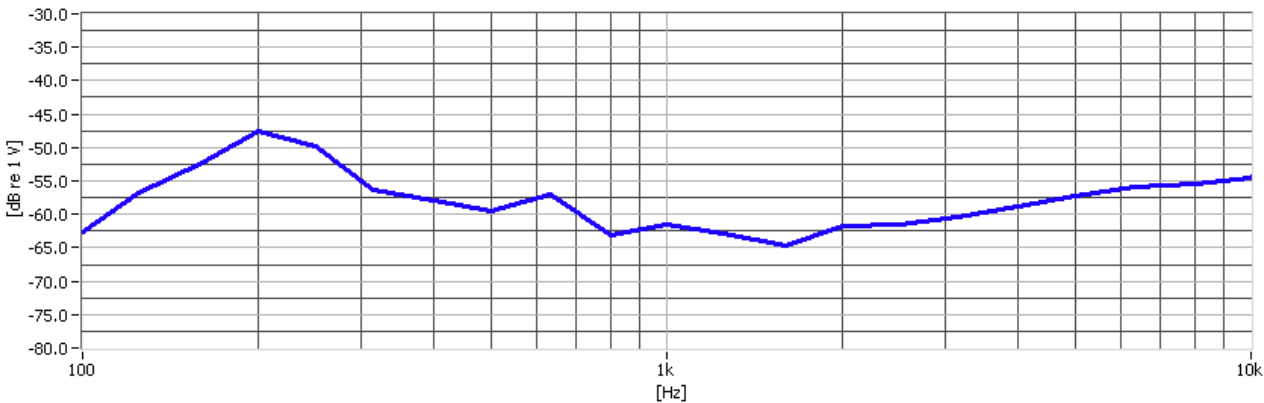
7.4 1KHz Vocoder Application Check

This model was verified to be within the linear region for ABM1 measurements. Two type of modes were tested in the axial configuration above the ABM1 maximum location/configuration derived from Table 7-1 & Table 7-2.



7.5 Undesirable Audio Magnetic Band Plot (ABM2)

XY Graph 1



Note : This plot represents the data from the location/configuration resulting in the highest ABM2 result regarding Table 7-2 for CDMA

7.6 T-coil Validation Test Results

XY Graph 1

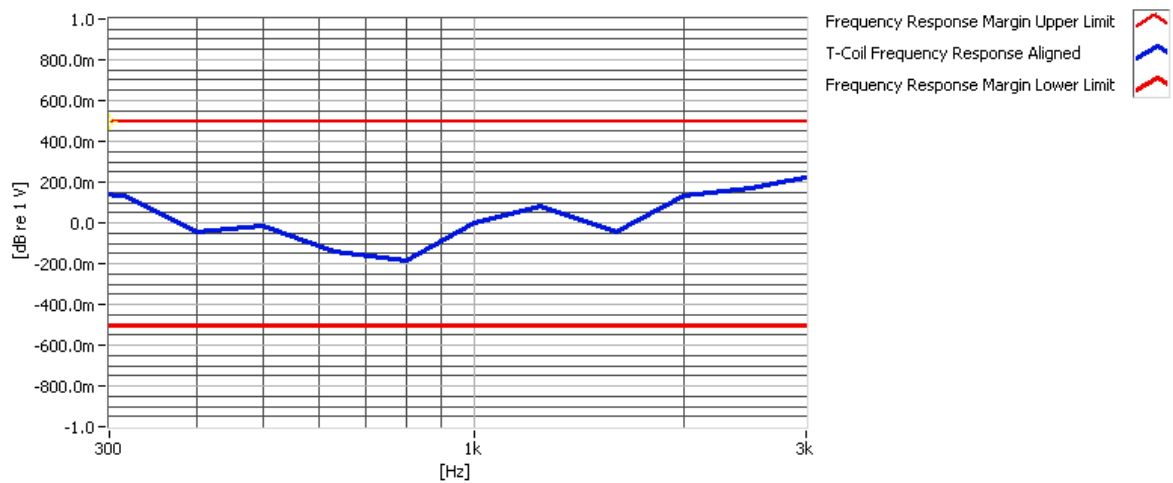


Figure 7-1
Helmholtz coil Validation for Frequency Response

Table 7-3
Table of Results for Helmholtz coil and Noise Validation

Orientation	Item	Target	Measured dB	Verdict
Helmholtz coil validation				
Axial	Frequency Response	0 ±0.5dB	0.27	PASS
	Magnetic Intensity, 0 dBA/m	0 ±0.5dB	0.001	PASS
Radial	Frequency Response	0 ±0.5dB	0.27	PASS
	Magnetic Intensity, 0 dBA/m	0 ±0.5dB	0.038	PASS
Noise Validation				
Axial		< -58dBA/m	-60.29	PASS
Radial Transverse		< -58dBA/m	-59.06	PASS
Radial Longitudinal		< -58dBA/m	-58.66	PASS

8. Conclusion

The measurements indicate that the wireless communications device complies with the HAC limits specified in accordance with the ANSI C63.19 standard and FCC WT Docket No. 01-309 RM-8658. Precise laboratory measures were taken to assure repeatability of the tests. The tested device complies with the requirements in respect to all parameters specific to the test. The test results and statements relate only to the item tested.

The measurement system and techniques presented in this evaluation are proposed in the ANSI standard as a means of best approximating wireless device compatibility with a hearing-aid. The literature is under continual re-construction.

9. Reference

- [1] ANSI C63.19-2007, American National Standard for Methods of Measurement of Compatibility between Wireless communication devices and Hearing Aids.", New York, NY, IEEE, June. 2008.
- [2] FCC Public Notice DA 06-1215, Wireless Telecommunications Bureau and Office of Engineering and Technology Clarify Use of Revised Wireless Phone Hearing Aid Compatibility Standard, June 6, 2006
- [3] FCC 3G Review Guidance, Laboratory Division OET FCC, Oct 2007
- [4] Berger, H. S., "Compatibility Between Hearing Aids and Wireless Devices," Electronic Industries Forum, Boston, MA, May, 1997
- [5] Berger, H. S., "Hearing Aid and Cellular Phone Compatibility: Working Toward Solutions," Wireless Telephones and Hearing Aids: New Challenges for Audiology, Gallaudet University, Washington, D.C., May, 1997 (To be reprinted in the American Journal of Audiology).
- [6] Berger, H. S., "Hearing Aid Compatibility with Wireless Communications Devices," IEEE International Symposium on Electromagnetic Compatibility, Austin, TX, August, 1997.
- [7] Bronaugh, E. L., "Simplifying EMI Immunity (Susceptibility) Tests in TEM Cells," in the 1990 IEEE International Symposium on Electromagnetic Compatibility Symposium Record, Washington, D.C., August 1990, pp. 488-491
- [8] Byrne, D. and Dillon, H., The National Acoustics Laboratory (NAL) New Procedure for Selecting the Gain and Frequency Response of a Hearing Aid, Ear and Hearing 7:257-265, 1986.
- [9] Crawford, M. L., "Measurement of Electromagnetic Radiation from Electronic Equipment using TEM Transmission Cells," U.S. Department of Commerce, National Bureau of Standards, NBSIR 73-306, Feb. 1973.
- [10] Crawford, M. L., and Workman, J. L., "Using a TEM Cell for EMC Measurements of Electronic Equipment," U.S. Department of Commerce, National Bureau of Standards. Technical Note 1013, July 1981.
- [11] EHIMA GSM Project, Development phase, Project Report (1st part) Revision A. Technical-Audiological Laboratory and Telecom Denmark, October 1993.
- [12] EHIMA GSM Project, Development phase, Part II Project Report. Technical-Audiological Laboratory and Telecom Denmark, June 1994.
- [13] EHIMA GSM Project Final Report, Hearing Aids and GSM Mobile Telephones: Interference Problems, Methods of Measurement and Levels of Immunity. Technical-Audiological Laboratory and Telecom Denmark, 1995.
- [14] HAMPIS Report, Comparison of Mobile phone electromagnetic near field with an upscaled electromagnetic far field, using hearing aid as reference, 21 October 1999.
- [15] Hearing Aids/GSM, Report from OTWIDAM, Technical-Audiological Laboratory and Telecom Denmark, April 1993.
- [16] IEEE 100, The Authoritative Dictionary of IEEE Standards Terms, Seventh Edition.

- [17] Joyner, K. H., et. al., Interference to Hearing Aids by the New Digital Mobile Telephone System, Global System for Mobile (GSM) Communication Standard, National Acoustic Laboratory, Australian Hearing Series, Sydney 1993.
- [18] Joyner, K. H., et. al., Interference to Hearing Aids by the Digital Mobile Telephone System, Global System for Mobile Communications (GSM), NAL Report #131, National Acoustic Laboratory Australian Hearing Series, Sydney, 1995.
- [19] Keeker, W. T., Crawford, M. L., and Wilson, W. A., "Construction of a Transverse Electromagnetic Cell", U.S. Department of Commerce, National Bureau of Standards, Technical Note 1011, Nov. 1978.
- [20] Konigstein, D., and Hansen, D., "A New Family of TEM Cells with enlarged bandwidth and Optimized working Volume," in the Proceedings of the 7th International Symposium on EMC, Zurich, Switzerland, March 1987; 50:9, pp. 127-132.
- [21] Kuk, F., and Hjorstgaard, N. K., "Factors affecting interference from digital cellular telephones, " Hearing Journal, 1997; 50:9, pp 32-34.
- [22] Ma, M. A., and Kanda, M., "Electromagnetic Compatibility and Interference Metrology," U.S. Department of Commerce, National Bureau of Standards, Technical Note 1099, July 1986, pp.17-43.
- [23] Ma, M. A., Sreenivashiah, I. , and Chang, D. C., "A Method of Determining the Emission and Susceptibility Levels of Electrically Small Objects Using a TEM Cell," U.S. Department of Commerce, National Bureau of Standards, Technial Note 1040, July 1981.
- [24] McCandless, G. A., and Lyregaard, P. E., Prescription of Gain/Output (POGO) for Hearing Aids, Hearing Instruments 1:16-21, 1983
- [25] Skopec, M., "Hearing Aid Electromagnetic Interference from Digital Wireless Telephones, "IEEE Transactions on Rehabilitation Engineering, vol. 6, no. 2, pp. 235-239, June 1998.
- [26] Technical Report, GSM 05.90, GSM EMC Considerations, European Telecommunications Standards Institute, January 1993.
- [27] Victorian, T. A., "Digital Cellular Telephone Interference and Hearing Aid Compatibility—an Update," Hearing Journal 1998; 51:10, pp. 53-60
- [28] Wong, G. S. K., and Embleton, T. F. W., eds., AIP Handbook of Condenser Microphones: Theory, Calibration and Measurements, AIP Press.

West Caldwell Calibration Laboratories Inc.

Certificate of Calibration

for

AXIAL T COIL PROBE

Manufactured by: TEM CONSULTING
Model No: AXIAL T COIL PROBE
Serial No: TEM-1115
Calibration Recall No: 20385

Submitted By:

Customer: STEVE LIU
Company: PCTEST ENGINEERING LAB
Address: 6660-B DOBBIN ROAD
COLUMBIA MD 21045

The subject instrument was calibrated to the indicated specification using standards traceable to the National Institute of Standards and Technology or to accepted values of natural physical constants. This document certifies that the instrument met the following specification upon its return to the submitter.

West Caldwell Calibration Laboratories Procedure No. AXIAL T C TEM

Upon receipt for Calibration, the instrument was found to be:

Within (X) see attached Report of Calibration.

the tolerance of the indicated specification.

West Caldwell Calibration Laboratorie's calibration control system meets the following requirements, ISO 10012-1 MIL STD 45662A, ANSI/NC SL Z540-1, IEC Guide 25, ISO 9001:2008 and ISO 17025

Note: With this Certificate, Report of Calibration is included.

Approved by:

Calibration Date: 14-Jan-11

Certificate No: 20385 - 2

QA Doc. #1051 Rev. 2.0 10/1/01

Certificate Page 1 of 1


Felix Christopher
Quality Manager

West Caldwell Calibration Laboratories, Inc.
uncompromised calibration
1575 State Route 96, Victor, NY 14564, U.S.A.

ISO 9001:2008
Registered Company
Calibration Traceable
to N.I.S.T.

Phone: (585) 586-3900 Fax: (585) 586-4327





1575 State Route 96, Victor NY 14564

ACCREDITATION
ISO/IEC 17025

1533.01

REPORT OF CALIBRATION

TEM Consulting LP Axial T Coil Probe

for
Model No.: Axial T Coil Probe

Serial No.: TEM-1115

Company : PC Test Inc.

I. D. No: XXXX

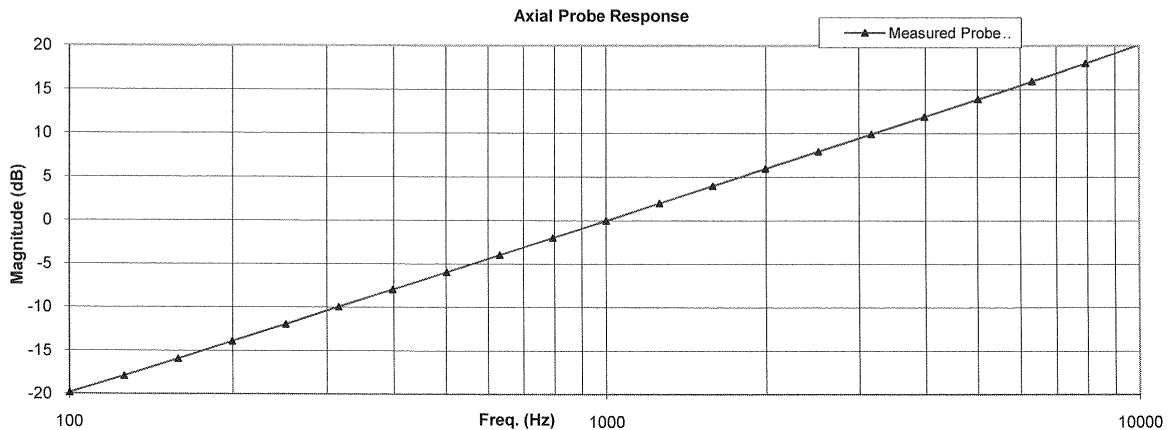
Calibration results:			Before data:		After data:	
Probe Sensitivity measured with Helmholtz Coil						
<i>Helmholtz Coil;</i>			Before & after data same: ...X.....			
the number of turns on each coil;	10	No.	Laboratory Environment:			
the radius of each coil, in meters;	0.204	m	Ambient Temperature: 24.4 °C			
the current in the coils, in amperes.;	0.08	A	Ambient Humidity: 27.6 % RH			
<i>Helmholtz Coil Constant;</i>	6.98	A/m/V	Ambient Pressure: 100.3 kPa			
<i>Helmholtz Coil magnetic field;</i>	5.93	A/m	Calibration Date: 14-Jan-11 3:26 PM			
Probe Sensitivity at	1000	Hz.	Re-calibration Due: 14-Jan-12			
was	-60.20	dBV/A/m	Report Number: 20385 -2			
	0.978	mV/A/m	Control Number: 20385			
Probe resistance	888	Ohms				
The above listed instrument meets or exceeds the tested manufacturer's specifications.						
This Calibration is traceable through NIST test numbers:			,205342			
The expanded uncertainty of calibration: 0.30dB at 95% confidence level with a coverage factor of k=2.						

The above listed instrument meets or exceeds the tested manufacturer's specifications.

This Calibration is traceable through NIST test numbers: ,205342

The expanded uncertainty of calibration: 0.30dB at 95% confidence level with a coverage factor of k=2.

Graph represents Probes Frequency Response.



The above listed instrument was checked using calibration procedure documented in West Caldwell Calibration Laboratories Inc. procedure :

Rev. 5.0 Sept. 10, 2010 Doc. # 1038 HCATEMC

Calibration was performed by West Caldwell Calibration Laboratories Inc. under Operating Procedures

intended to implement the requirements of ISO10012-1, IEC Guide 25, ANSI/NCSS Z540-1, (MIL-STD-45662A) and ISO 9001:2008, ISO 17025

Cal. Date: 14-Jan-2011 3:26 PM

Measurements performed by:

Calibrated on WCCL system type 9700

Felix Christopher

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Rev. 5.0 Sept. 10, 2010 Doc. # 1038 HCATEMC

HCATEMC_TEM-1115_Jan-14-2011

West Caldwell Calibration Laboratories Inc.

1575 State Route 96, Victor NY 14564
Tel. (585) 586-3900 FAX (585) 586-4327

Calibration Data Record

for
TEM Consulting LP Axial T Coil Probe Model No.: Axial T Coil Probe Serial No.: TEM-1115
Company : PC Test Inc.

Test	Function	Tolerance	Measured values		
			Before	Out	Remarks
1.0	Probe Sensitivity at	1000 Hz. dBV/A/m	-60.20		
2.0	Probe Level Linearity	dB			
		6	6.02		
		Ref. (0 dB)	0	0.00	
		-6	-6.02		
		-12	-12.03		
3.0	Probe Frequency Response	Hz			
		100	-19.8		
		126	-17.9		
		158	-15.9		
		200	-13.9		
		251	-11.9		
		316	-9.9		
		398	-8.0		
		501	-6.0		
		631	-4.0		
		794	-2.0		
		Ref. (0 dB)	1000	0.0	
			1259	2.0	
			1585	4.0	
			1995	6.0	
			2512	7.9	
			3162	9.9	
			3981	11.9	
			5012	13.9	
			6310	15.9	
			7943	18.0	
			10000	20.1	

Instruments used for calibration:			Date of Cal.	Traceability No.	Due Date
HP	34401A	S/N US360641	8-Nov-2010	,205342	8-Nov-2011
HP	34401A	S/N US361024	8-Nov-2010	,205342	8-Nov-2011
HP	33120A	S/N S3604371	8-Nov-2010	,205342	8-Nov-2011
B&K	2133	S/N 1492410	1-Oct-2010	822/278767-10	1-Oct-2011

Cal. Date: 14-Jan-2011 3:26 PM
Calibrated on WCCL system type 9700

Tested by: Felix Christopher

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Rev. 5.0 Sept. 10, 2010 Doc. # 1038 HCATEMC

West Caldwell Calibration Laboratories Inc.

Certificate of Calibration

for

RADIAL T COIL PROBE

Manufactured by: TEM CONSULTING
Model No: RADIAL T COIL PROBE
Serial No: TEM-1119
Calibration Recall No: 20385

Submitted By:

Customer: STEVE LIU
Company: PCTEST ENGINEERING LAB
Address: 6660-B DOBBIN ROAD
COLUMBIA MD 21045

The subject instrument was calibrated to the indicated specification using standards traceable to the National Institute of Standards and Technology or to accepted values of natural physical constants. This document certifies that the instrument met the following specification upon its return to the submitter.

West Caldwell Calibration Laboratories Procedure No. RADIAL T TEM

Upon receipt for Calibration, the instrument was found to be:

Within (X) see attached Report of Calibration.

the tolerance of the indicated specification.

West Caldwell Calibration Laboratorie's calibration control system meets the following requirements, ISO 10012-1 MIL STD 45662A, ANSI/NC SL Z540-1, IEC Guide 25, ISO 9001:2008 and ISO 17025

Note: With this Certificate, Report of Calibration is included.

Approved by:

Calibration Date: 14-Jan-11

Certificate No: 20385 - 1

QA Doc. #1051 Rev. 2.0 10/1/01

Certificate Page 1 of 1

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Quality Manager

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Phone: (585) 586-3900 Fax: (585) 586-4327



O.K. to use
2011.6.16



1575 State Route 96, Victor NY 14564



REPORT OF CALIBRATION

TEM Consulting LP Radial T Coil Probe

for
Model No.: Radial T Coil Probe

Serial No.: TEM-1119

Company : PC Test Inc.

I. D. No: XXXX

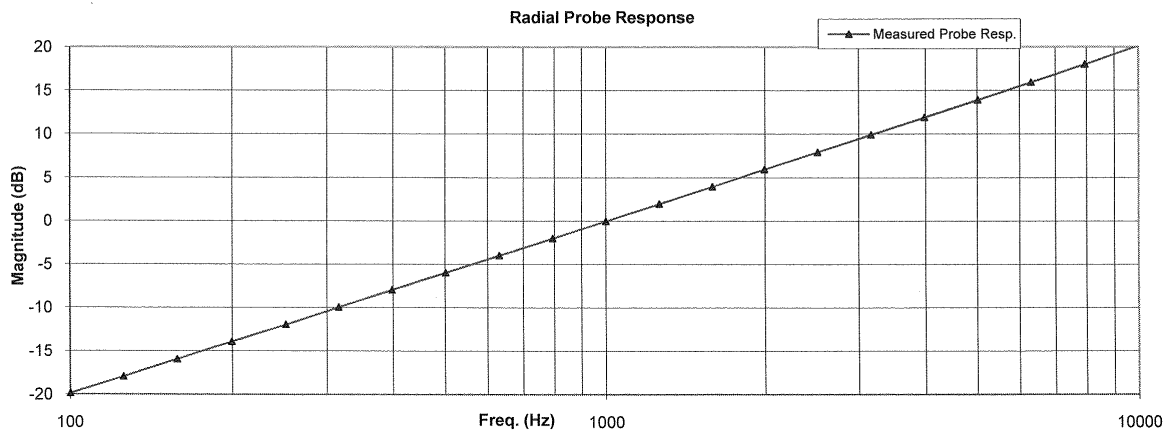
Calibration results:			Before data:		After data:	
Probe Sensitivity measured with Helmholtz Coil						
<i>Helmholtz Coil;</i>			Before & after data same: ...X.....			
the number of turns on each coil;	10	No.				
the radius of each coil, in meters;	0.204	m				
the current in the coils, in amperes.;	0.08	A	Laboratory Environment:			
<i>Helmholtz Coil Constant;</i>	6.99	A/m/V	Ambient Temperature:	24.4	°C	
<i>Helmholtz Coil magnetic field;</i>	5.92	A/m	Ambient Humidity:	27.6	% RH	
			Ambient Pressure:	100.3	kPa	
			Calibration Date:	14-Jan-11	5:27 PM	
Probe Sensitivity at	1000	Hz.	Re-calibration Due:	14-Jan-12		
was	-60.18	dBV/A/m	Report Number:	20385	-1	
	0.979	mV/A/m	Control Number:	20385		
Probe resistance	890	Ohms				
The above listed instrument meets or exceeds the tested manufacturer's specifications.						
This Calibration is traceable through NIST test numbers:			,205342			
The expanded uncertainty of calibration: 0.28dB at 95% confidence level with a coverage factor of k=2.						

The above listed instrument meets or exceeds the tested manufacturer's specifications.

This Calibration is traceable through NIST test numbers: ,205342

The expanded uncertainty of calibration: 0.28dB at 95% confidence level with a coverage factor of k=2.

Graph represents Probes Frequency Response.



The above listed instrument was checked using calibration procedure documented in West Caldwell

Calibration Laboratories Inc. procedure :

Rev. 5.0 Sept. 10, 2010 Doc. # 1038 HCRTEMC

Calibration was performed by West Caldwell Calibration Laboratories Inc. under Operating Procedures

intended to implement the requirements of ISO10012-1, IEC Guide 25, ANSI/NCSL Z540-1, (MIL-STD-45662A) and ISO 9001:2008, ISO 17025

Cal. Date: 14-Jan-2011 5:27 PM

Measurements performed by:

Calibrated on WCCL system type 9700

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West Caldwell Calibration Laboratories Inc.

1575 State Route 96, Victor NY 14564

Tel. (585) 586-3900 FAX (585) 586-4327

Calibration Data Record

TEM Consulting LP Radial T Coil Probe

for
Model No.: Radial T Coil Probe

Serial No.: TEM-1119

Company : PC Test Inc.

Test	Function	Tolerance	Measured values		
			Before	Out	Remarks
1.0	Probe Sensitivity at	1000 Hz. dBV/A/m	-60.18		
2.0	Probe Level Linearity	dB			
		6	6.03		
		Ref. (0 dB) 0	0.00		
		-6	-6.02		
		-12	-12.03		
3.0	Probe Frequency Response	Hz			
		100	-19.8		
		126	-17.9		
		158	-15.9		
		200	-13.9		
		251	-11.9		
		316	-9.9		
		398	-8.0		
		501	-6.0		
		631	-4.0		
		794	-2.0		
		Ref. (0 dB) 1000	0.0		
		1259	2.0		
		1585	4.0		
		1995	6.0		
		2512	7.9		
		3162	9.9		
		3981	11.9		
		5012	13.9		
		6310	15.9		
		7943	18.0		
		10000	20.1		

Instruments used for calibration:				Date of Cal.	Traceability No.	Due Date
HP	34401A	S/N	US360641	8-Nov-2010	,205342	8-Nov-2011
HP	34401A	S/N	US361024	8-Nov-2010	,205342	8-Nov-2011
HP	33120A	S/N	S3604371	8-Nov-2010	,205342	8-Nov-2011
B&K	2133	S/N	1492410	1-Oct-2010	822/278767-10	1-Oct-2011

Cal. Date: 14-Jan-2011 5:27 PM

Tested by: Felix Christopher

Calibrated on WCCL system type 9700

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